į	S	e	arc	:h	No	ote	S
•					21110		1111



Application/Control No.	Applicant(s)/Patent under Reexamination	
10/566,237	YASUI ET AL.	
Examiner	Art Unit	
HIEU T. VO	3747	

SEARCHED			
Class	Subclass	Date	Examiner
701	102 114 115	11/26/2006	∨H
123	90.15	11/26/2006	VH
123	90.17	11/26/2006	VH
	·		
			,

INT	INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner	
All of above		11/26/2006	VH	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST	11/26/2006	VH